



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



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Product Summary

| BV_{DSS} | $R_{DS(ON)}$ | I_D $T_A = +25^\circ C$ |
|------------|---------------------------------|------------------------------|
| 30V | 460m Ω @ $V_{GS} = 4.5V$ | 1.1A |
| | 560m Ω @ $V_{GS} = 2.5V$ | 1.0A |

Description

This new generation MOSFET is designed to minimize the on-state resistance ($R_{DS(ON)}$) yet maintain superior switching performance, making it ideal for high-efficiency power-management applications.

Applications

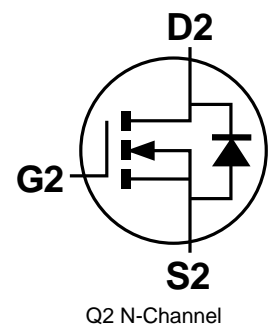
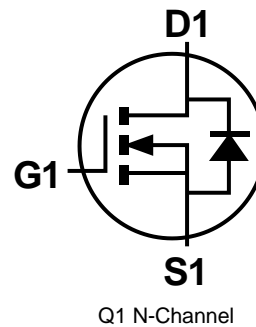
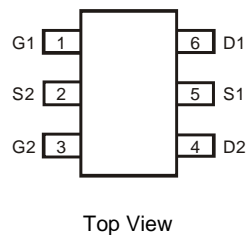
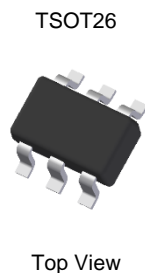
- Backlighting
- DC-DC converters
- Power-management functions

Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage

Mechanical Data

- Package: TSOT26
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See Diagram
- Terminals: Finish – Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (e3)
- Weight: 0.013 grams (Approximate)



Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

| Characteristic | | | Symbol | Value | Unit |
|--|--------------|--|------------------|------------|------|
| Drain-Source Voltage | | | V _{DSS} | 30 | V |
| Gate-Source Voltage | | | V _{GSS} | ±8 | V |
| Continuous Drain Current (Note 6) V _{GS} = 4.5V | Steady State | T _A = +25°C T _A = +70°C | I _D | 1.1 0.9 | A |
| Maximum Continuous Body Diode Forward Current (Note 6) | | | I _S | 0.72 | A |
| Pulsed Drain Current (10μs Pulse, Duty Cycle = 1%) | | | I _{DM} | 2.4 | A |

Thermal Characteristics

| Characteristic | Symbol | Value | Unit |
|--|-----------------------------------|-------------|------|
| Power Dissipation (Note 5) | P _D | 0.5 | W |
| Thermal Resistance, Junction to Ambient @T _A = +25°C (Note 5) | R _{θJA} | 252 | °C/W |
| Power Dissipation (Note 6) | P _D | 0.8 | W |
| Thermal Resistance, Junction to Ambient @T _A = +25°C (Note 6) | R _{θJA} | 150 | °C/W |
| Operating and Storage Temperature Range | T _J , T _{STG} | -55 to +150 | °C |

Electrical Characteristics – N-Channel (@T_A = +25°C, unless otherwise specified.)

| Characteristic | Symbol | Min | Typ | Max | Unit | Test Condition |
|---|---------------------|------|------|------|------|--|
| OFF CHARACTERISTICS (Note 7) | | | | | | |
| Drain-Source Breakdown Voltage | BV _{DSS} | 30 | — | — | V | V _{GS} = 0V, I _D = 10μA |
| Zero Gate Voltage Drain Current | I _{DSS} | — | — | 1 | μA | V _{DS} = 30V, V _{GS} = 0V |
| Gate-Source Leakage | I _{GSS} | — | — | ±10 | μA | V _{GS} = ±8V, V _{DS} = 0V |
| ON CHARACTERISTICS (Note 7) | | | | | | |
| Gate Threshold Voltage | V _{GS(TH)} | 0.45 | — | 0.95 | V | V _{DS} = V _{GS} , I _D = 250μA |
| Static Drain-Source On-Resistance | R _{DS(ON)} | — | 310 | 460 | mΩ | V _{GS} = 4.5V, I _D = 200mA |
| | | | 360 | 560 | | |
| | | | 430 | 730 | | |
| Diode Forward Voltage | V _{SD} | — | 0.7 | 1.2 | V | V _{GS} = 0V, I _S = 300mA |
| DYNAMIC CHARACTERISTICS (Note 8) | | | | | | |
| Input Capacitance | C _{iss} | — | 40.8 | — | pF | V _{DS} = 25V, V _{GS} = 0V, f = 1.0MHz |
| Output Capacitance | C _{oss} | — | 7.6 | — | | |
| Reverse Transfer Capacitance | C _{rss} | — | 4.6 | — | | |
| Total Gate Charge (V _{GS} = 10V) | Q _g | — | 0.9 | — | | |
| Gate-Source Charge | Q _{gs} | — | 0.05 | — | ns | V _{DS} = 15V, I _D = 1A |
| Gate-Drain Charge | Q _{gd} | — | 0.3 | — | | |
| Turn-On Delay Time | t _{D(ON)} | — | 1.1 | — | ns | V _{DS} = 10V, I _D = 1A V _{GS} = 10V, R _g = 6Ω |
| Turn-On Rise Time | t _R | — | 15.9 | — | | |
| Turn-Off Delay Time | t _{D(OFF)} | — | 20.7 | — | | |
| Turn-Off Fall Time | t _F | — | 20.0 | — | | |

- Notes:
- Device mounted on FR-4 substrate PCB, 2oz copper, with minimum recommended pad layout.
 - Device mounted on FR-4 substrate PCB, 2oz copper, with 1inch square copper plate.
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to production testing.

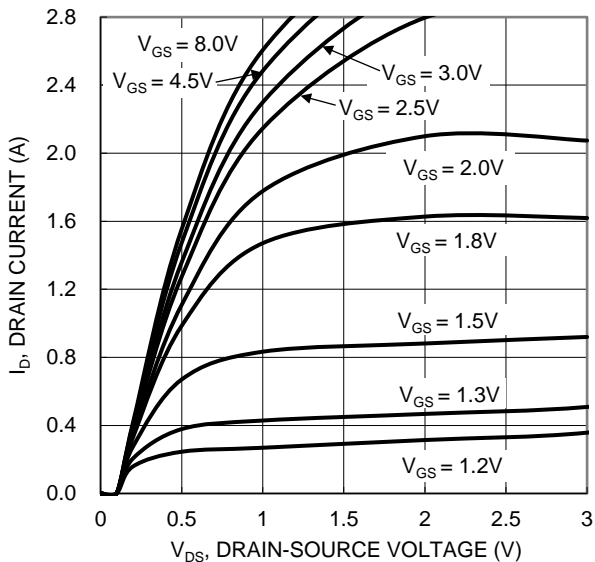


Figure 1. Typical Output Characteristic

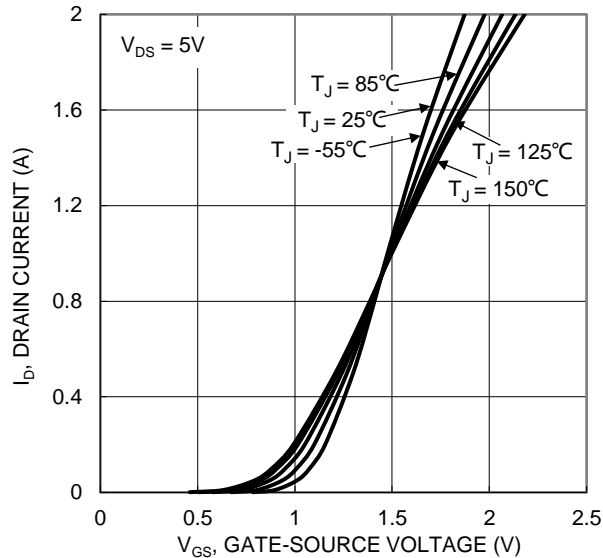


Figure 2. Typical Transfer Characteristic

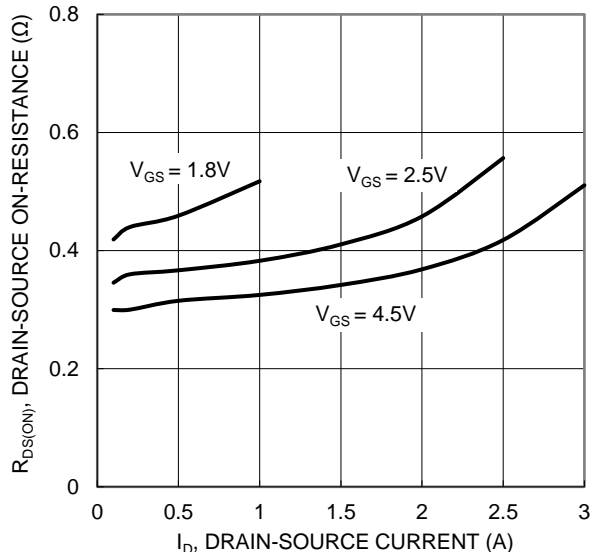


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

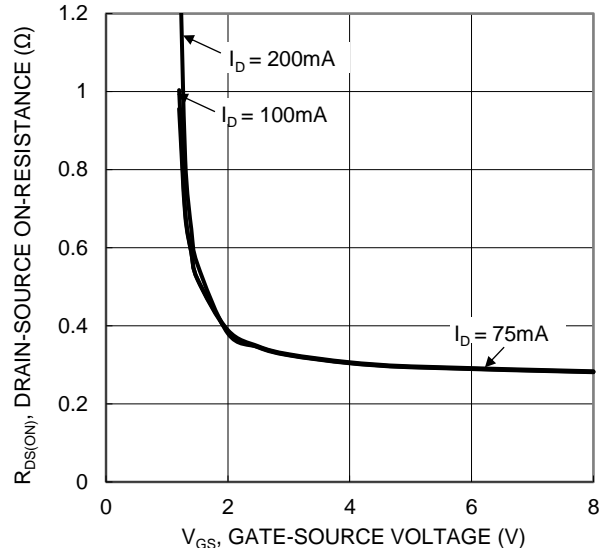


Figure 4. Typical Transfer Characteristic

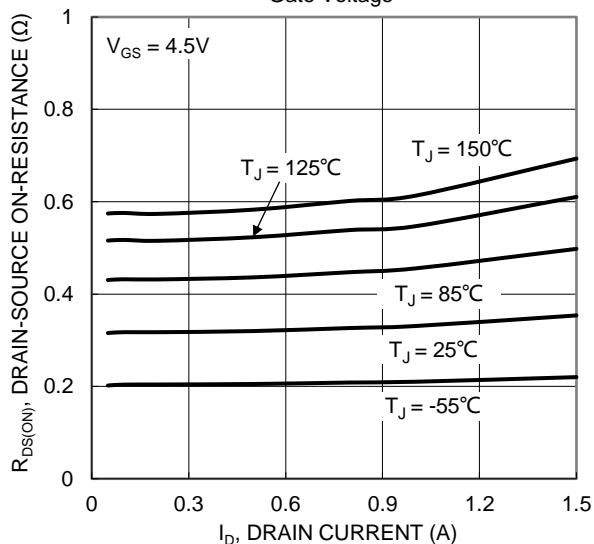


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

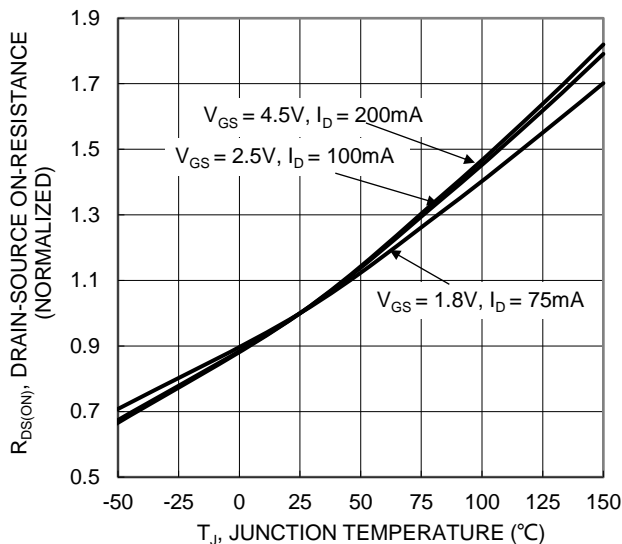


Figure 6. On-Resistance Variation with Junction Temperature

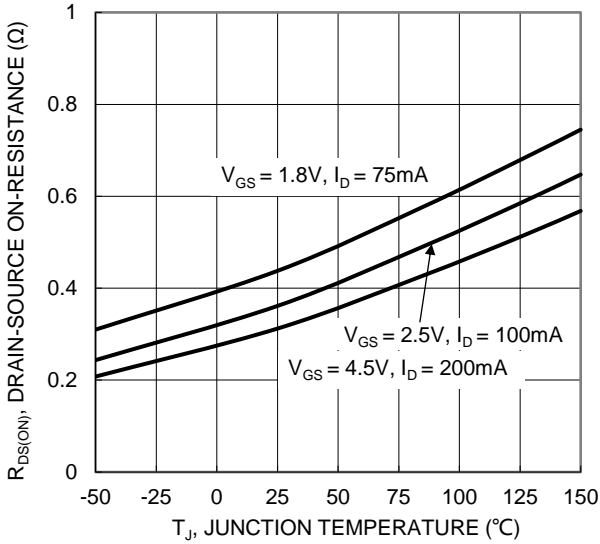


Figure 7. On-Resistance Variation with Junction Temperature

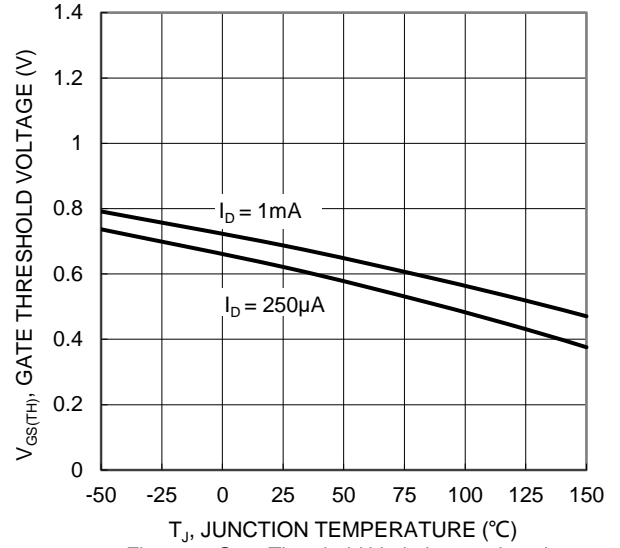


Figure 8. Gate Threshold Variation vs. Junction Temperature

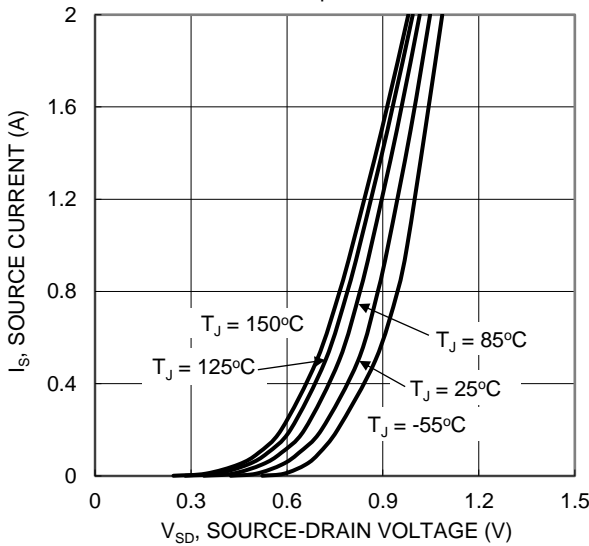


Figure 9. Diode Forward Voltage vs. Current

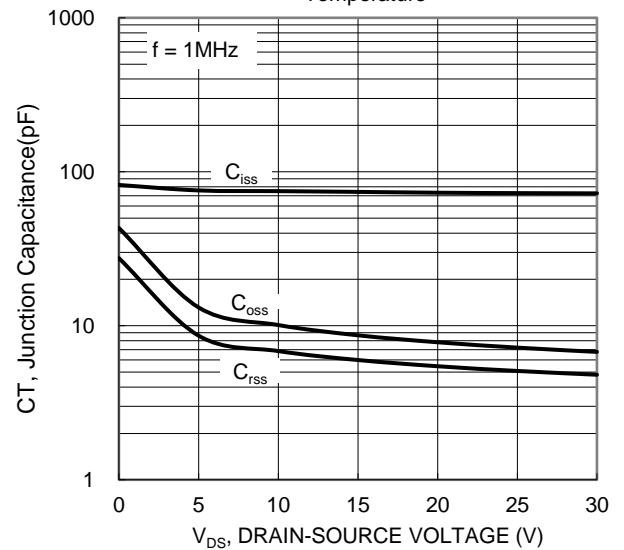


Figure 10. Typical Junction Capacitance

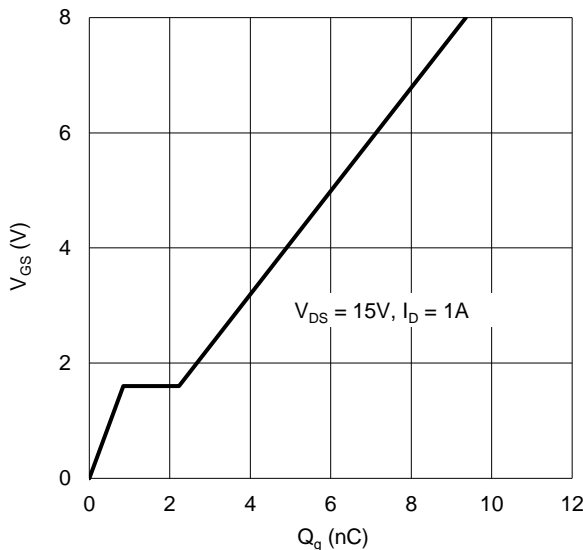


Figure 11. Gate Charge

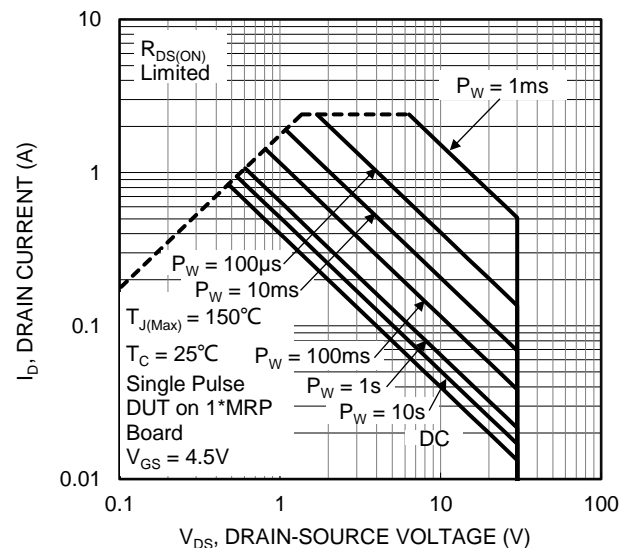


Figure 12. SOA, Safe Operation Area

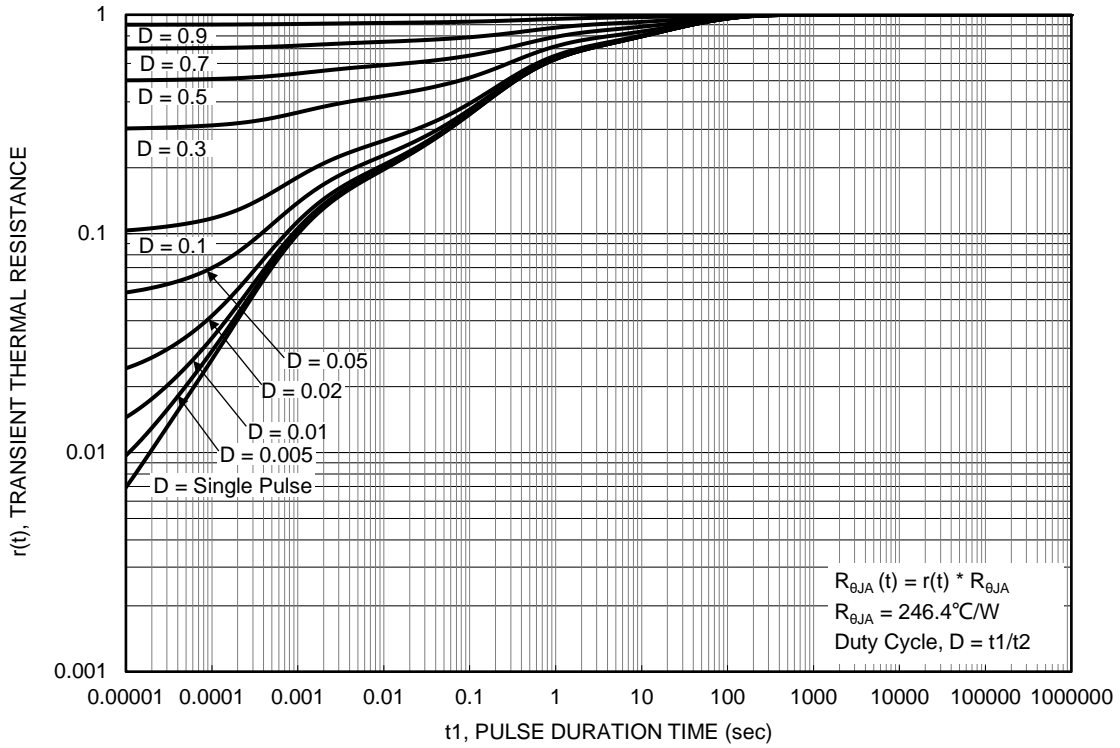
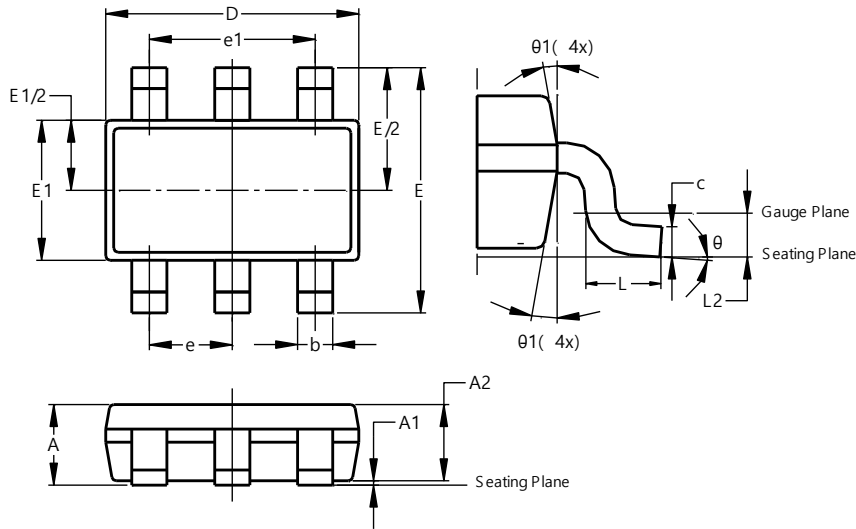


Figure 13. Transient Thermal Resistance

Package Outline Dimensions

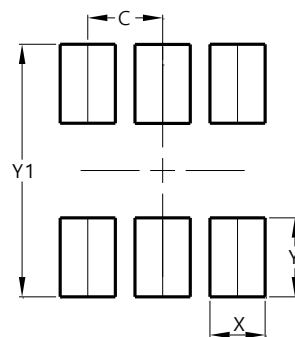
TSOT26



| TSOT26 | | | |
|-----------------------------|-----------|-------|-------|
| Dim | Min | Max | Typ |
| A | – | 1.00 | – |
| A1 | 0.010 | 0.100 | – |
| A2 | 0.840 | 0.900 | – |
| D | 2.800 | 3.000 | 2.900 |
| E | 2.800 BSC | | |
| E1 | 1.500 | 1.700 | 1.600 |
| b | 0.300 | 0.450 | – |
| c | 0.120 | 0.200 | – |
| e | 0.950 BSC | | |
| e1 | 1.900 BSC | | |
| L | 0.30 | 0.50 | – |
| L2 | 0.250 BSC | | |
| θ | 0° | 8° | 4° |
| $\theta 1$ | 4° | 12° | – |
| All Dimensions in mm | | | |

Suggested Pad Layout

TSOT26



| Dimensions | Value (in mm) |
|------------|---------------|
| C | 0.950 |
| X | 0.700 |
| Y | 1.000 |
| Y1 | 3.200 |